



IFX Gen2 SiC MOS increases EV Charger performance compared with Gen1 SiC MOS.

KM LEE



**The CoolSiC generation-2 (Gen2)
Introduction
(Page 3-13)**

Striving for excellence in SiC MOSFETs

Building on the strenghts of Generation 1 to enable the accelerated design of more cost optimized, efficient, compact, and reliable systems



- **CoolSiC™ Generation 1**

- Established the **benchmark in efficient power conversion**
- Solved the **gate oxide reliability** risk in SiC MOSFETs using a trench gate
- Overcame common SiC MOSFET limitations in **control and drive**
- Made **all industry-standard packages** available



Reliable performance

- **CoolSiC™ Generation 2**

- Enabling higher system performance per \$
- **Maintaining Gen1 high reliability**
- Adding **robustness and ease of use** features for **the highest design flexibility**
- Advancing the **packaging technology** for **more output capability**



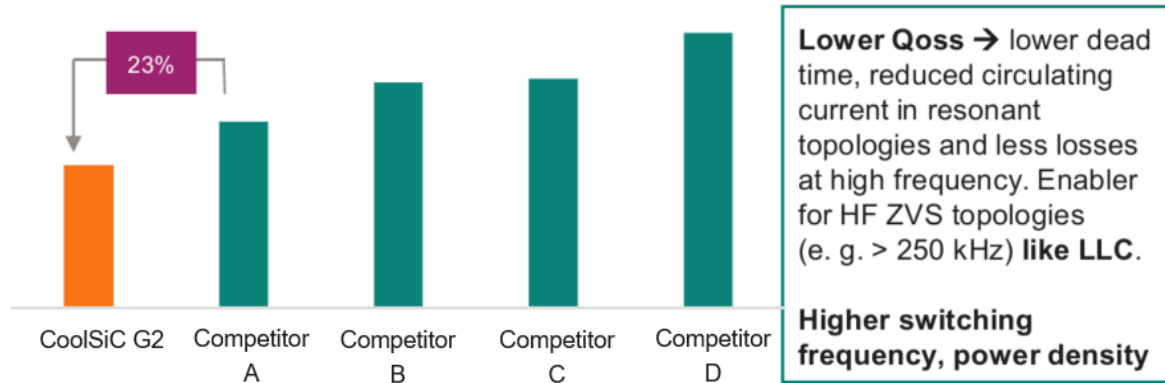
Unmatched industry leadership

CoolSiC gen2 shows the best FOMs to reach the highest performance and power density (25 °C comparison)

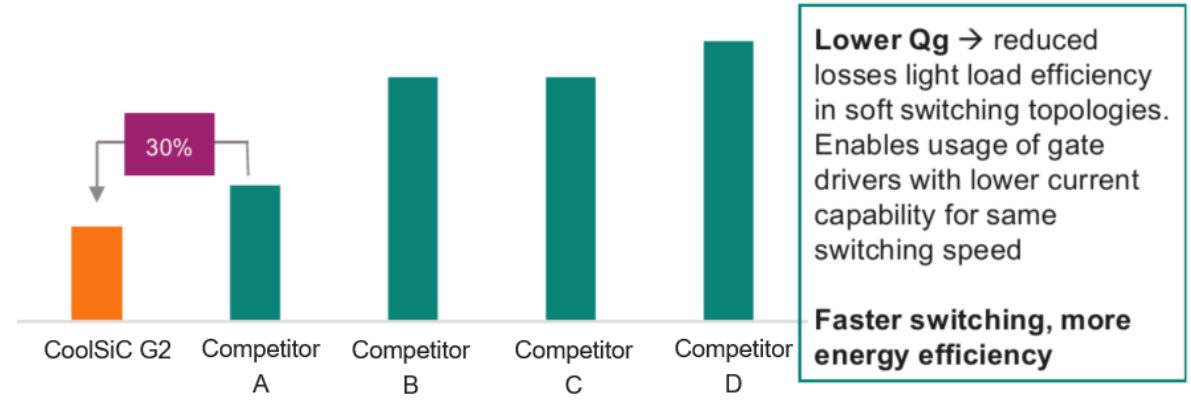


FoMs of competitor parts based on publicly available datasheets, 25°C, reference products:

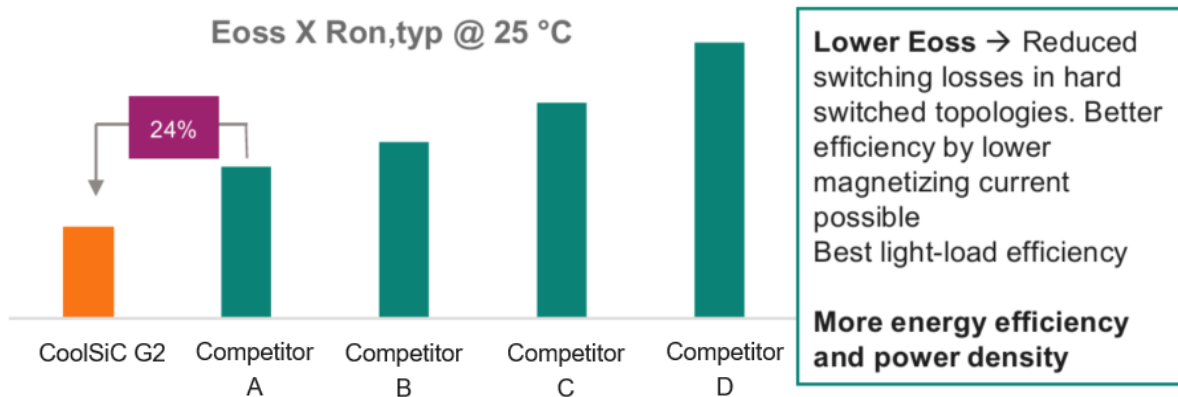
$Q_{oss} \times R_{on,typ} @ 25^\circ C$



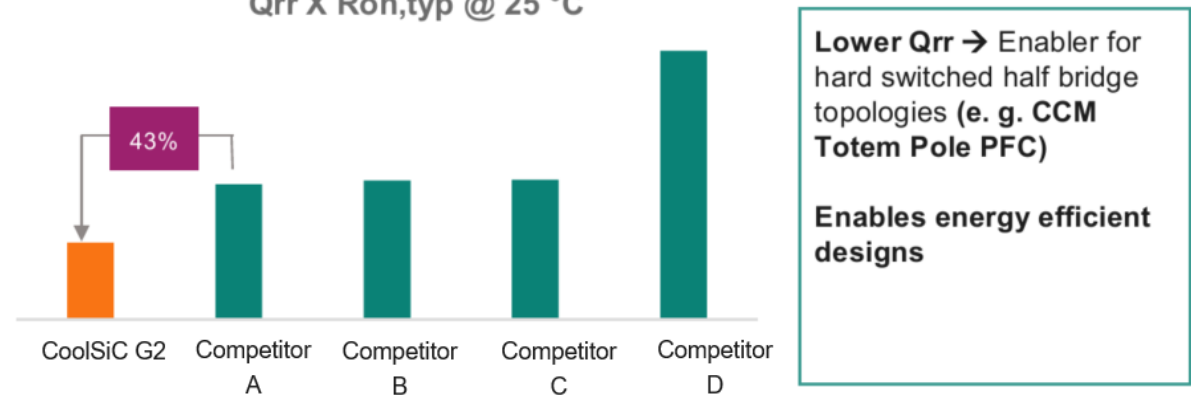
$Q_g \times R_{on,typ} @ 25^\circ C$



$E_{oss} \times R_{on,typ} @ 25^\circ C$



$Q_{rr} \times R_{on,typ} @ 25^\circ C$

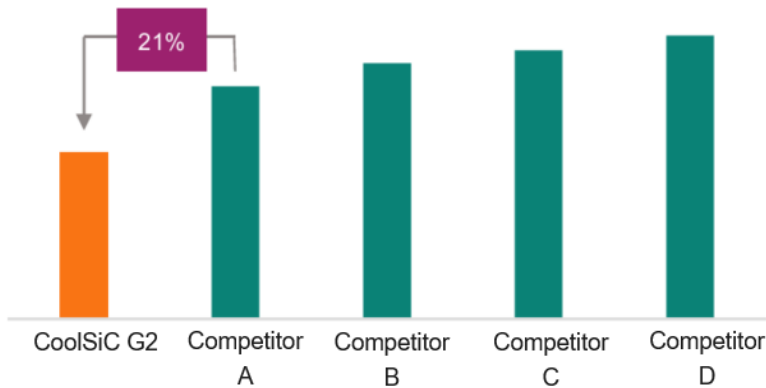


CoolSiC™ gen2 shows the best FOMs to reach the highest performance and power density (125 °C comparison)



FoMs of competitor parts based on publicly available datasheets, 125°C, reference products:

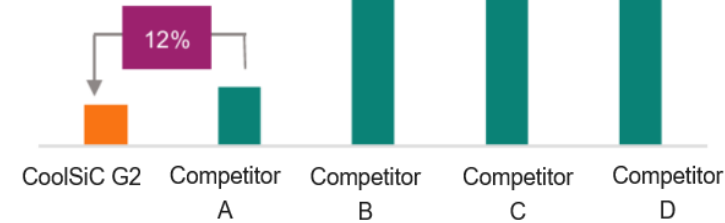
Qoss X Ron,typ @ 125°C



Lower Qoss → lower dead time, reduced circulating current in resonant topologies and less losses at high frequency. Enabler for HF ZVS topologies (e. g. > 250 kHz) like LLC.

Higher switching frequency, power density

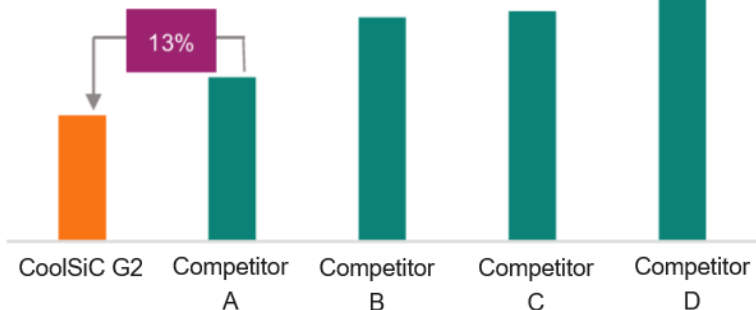
Qg X Ron,typ @ 125 °C



Lower Qg → reduced losses light load efficiency in HF resonant topologies. Enables usage of gate drivers with lower current capability for same switching speed

Faster switching, more energy efficiency

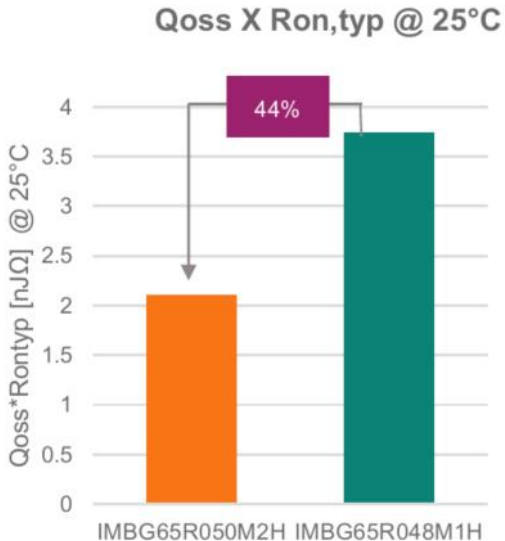
Eoss X Ron,typ @ 125 °C



Lower Eoss → Reduced switching losses in hard switched topologies. better efficiency by lower magnetizing current possible
Best light-load efficiency

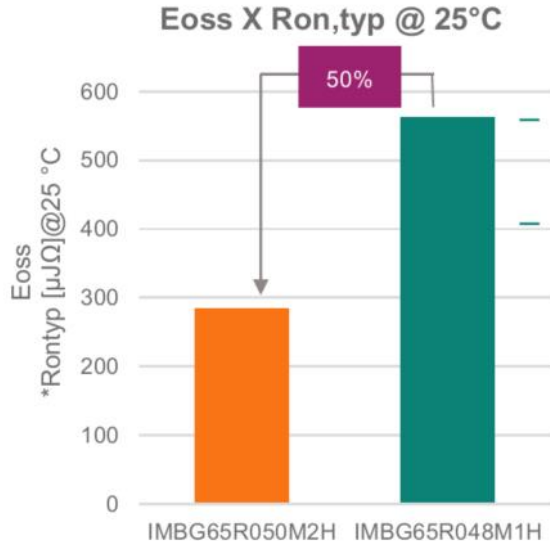
More energy efficiency and power density

CoolSiC™ gen2 performance compared to gen1



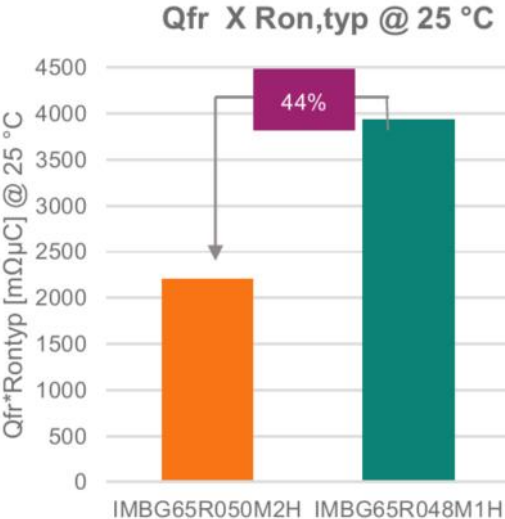
- Reduced Q_{oss} results in reduced current required for full ZVS.
- Reduced transition time for a given current.

Enabler for HF ZVS topologies (e. g. > 250 kHz)



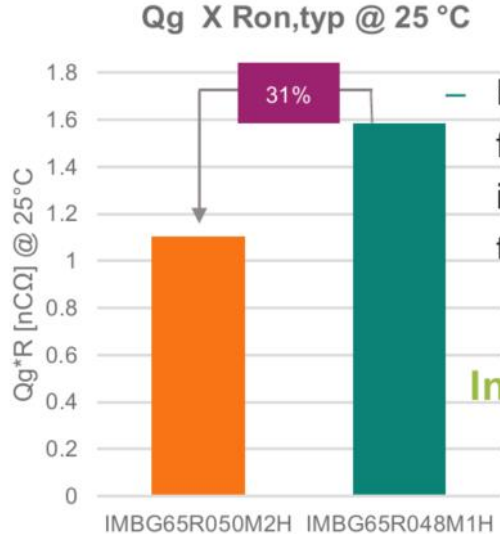
- Reduced E_{oss} results in reduced hard switching losses.
- Especially relevant in single ended topologies (e. g. Classic boost)

CoolSiC™ is effective also in single ended topologies



- Reduced Q_{fr} reduces switching losses and enables cycle by cycle hard commutation of body diode in totem pole like topologies.

Enabler for hard switched half bridge topologies (e. g. CCM Totem Pole PFC)



- Reduced gate driving losses help further improving light load efficiency in high frequency resonant topologies.

Increased light load efficiency in high frequency resonant topologies

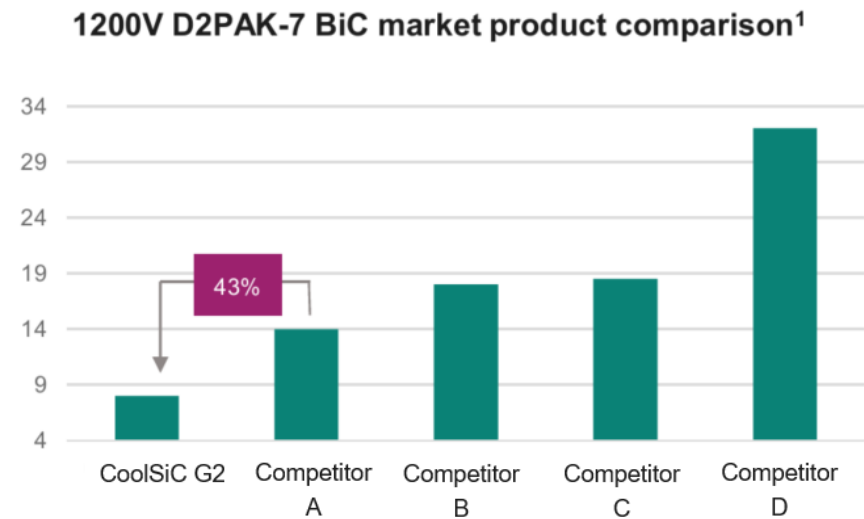
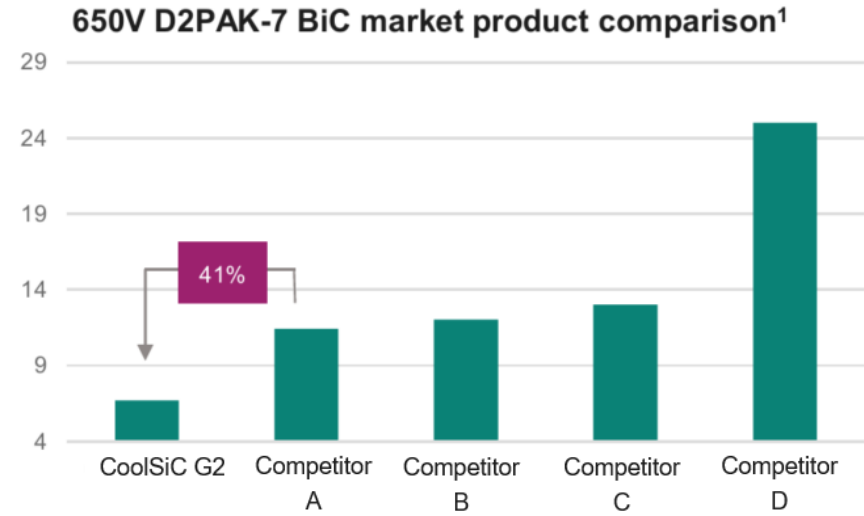
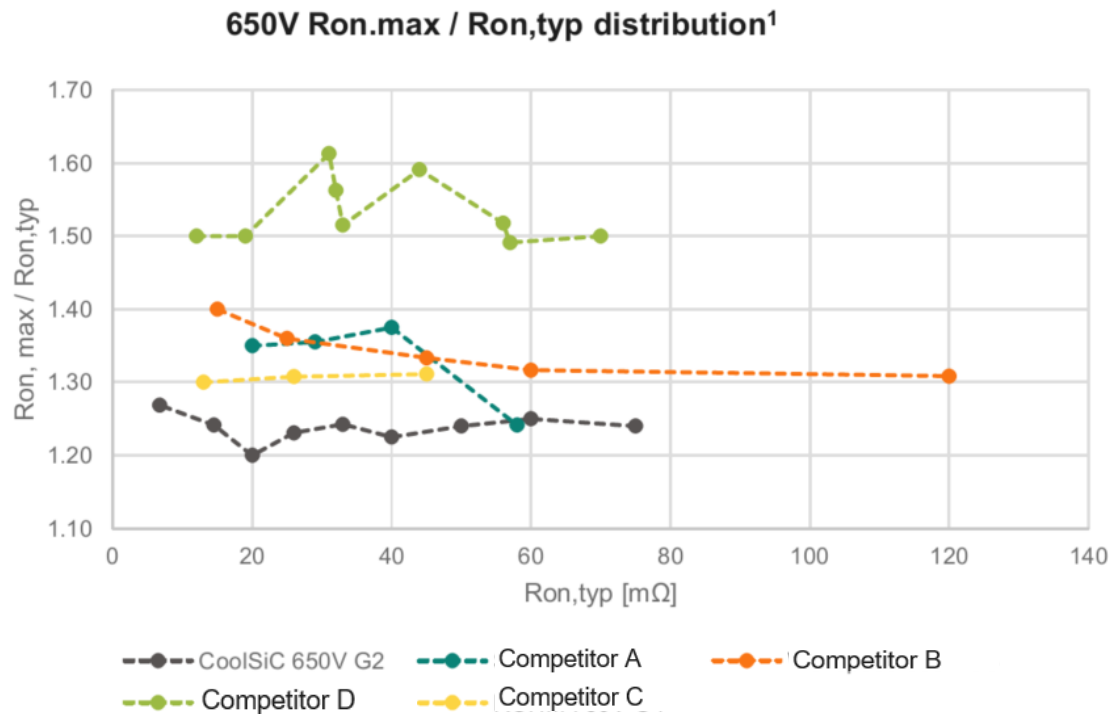


*Q_{fr} includes Q_{oss}

CoolSiC™ gen2 boasts the lowest RDson in SMD packages and the narrowest distribution



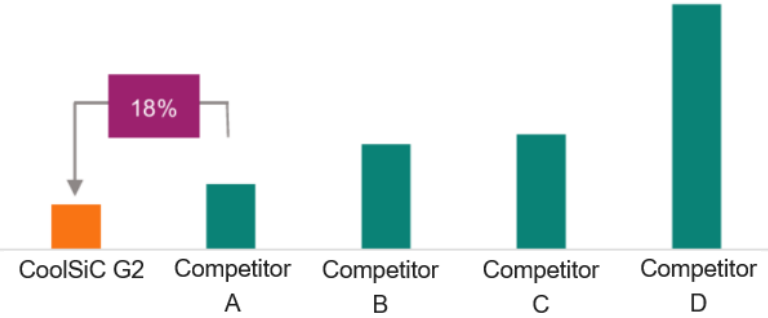
- CoolSiC™ G2 boasts the lowest Rdson in a standard SMD package (both in 650V and 1200V)
- It shows also the narrowest Rdson distribution



1) 650V and 1200V SiC MOSFET landscape as per Dec 2023. The 25°C values are reported

Low switches energies lead to lower power losses

Etot*Rontyp [nCΩ] @ 25 °C



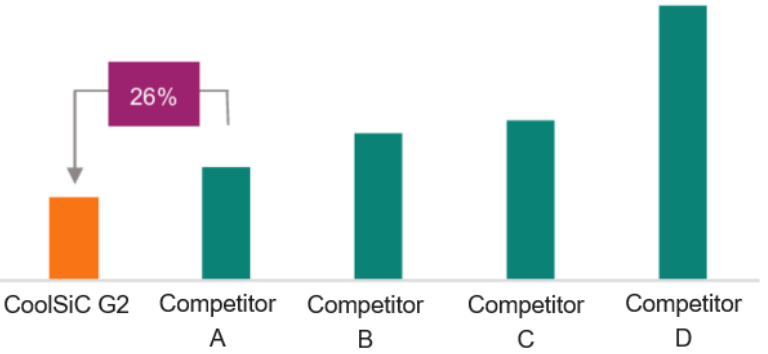
Lower Etot value enables lower power losses per installed Watt of system power

Test Condition

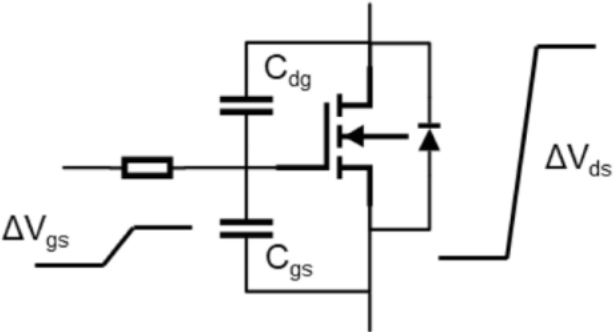
- Infineon, IMBG65R040M2H (Vds=400, Id=22.9A, Rg=3.3 Ohms, Vgs = -5 – 18V)
- Competitor A (Vds=400, Id=22.9A, Rg=3.3 Ohms, Vgs = -5 – 18V)
- Competitor B (Vds=500, Id=20.0A, Rg=3.3 Ohms, Vgs = -4 – 18V)
- Competitor C (Vds=400, Id=20.0A, Rg=3.3 Ohms, Vgs = -5 – 18V)
- Competitor D (Vds=400, Id=20.0A, Rg=3.3 Ohms, Vgs = -4 – 18V)

Measurements in Infineon labs, with Datasheets

Etot*Ronmax [nCΩ] @ 25 °C

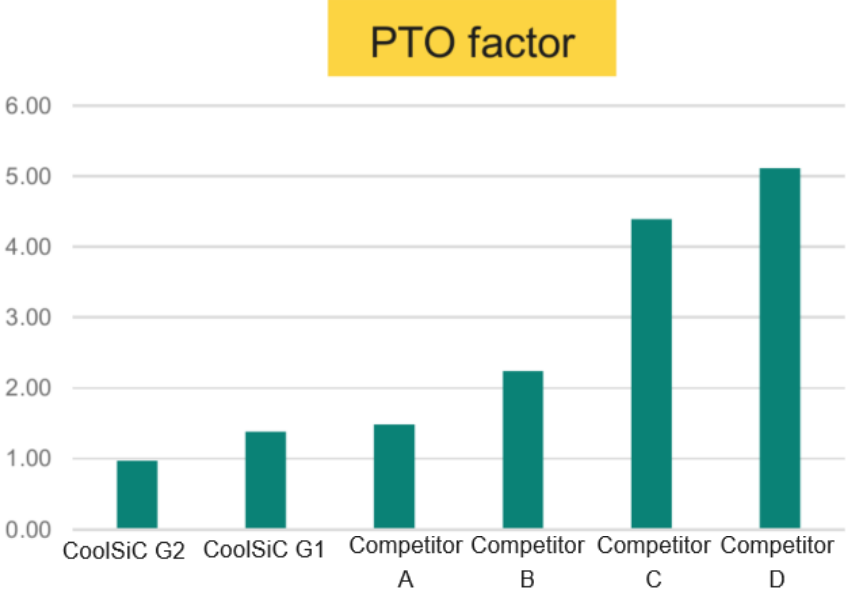


Best immunity against unwanted turn-on effects



- The lower is the PTO factor, the less likely is to have parasitic turn on → higher efficiency and safer implementation of unipolar drive
- Both 1200V and 650V show excellent immunity against PTO. Below is reported, as example, a 650V / 750V PTO SiC MOSFET factor comparison

- Parasitic (re)turn on (PTO) happens when the induced voltage on the gate is higher than the V_{th} – threshold voltage
- PTO may increase the turn-on losses

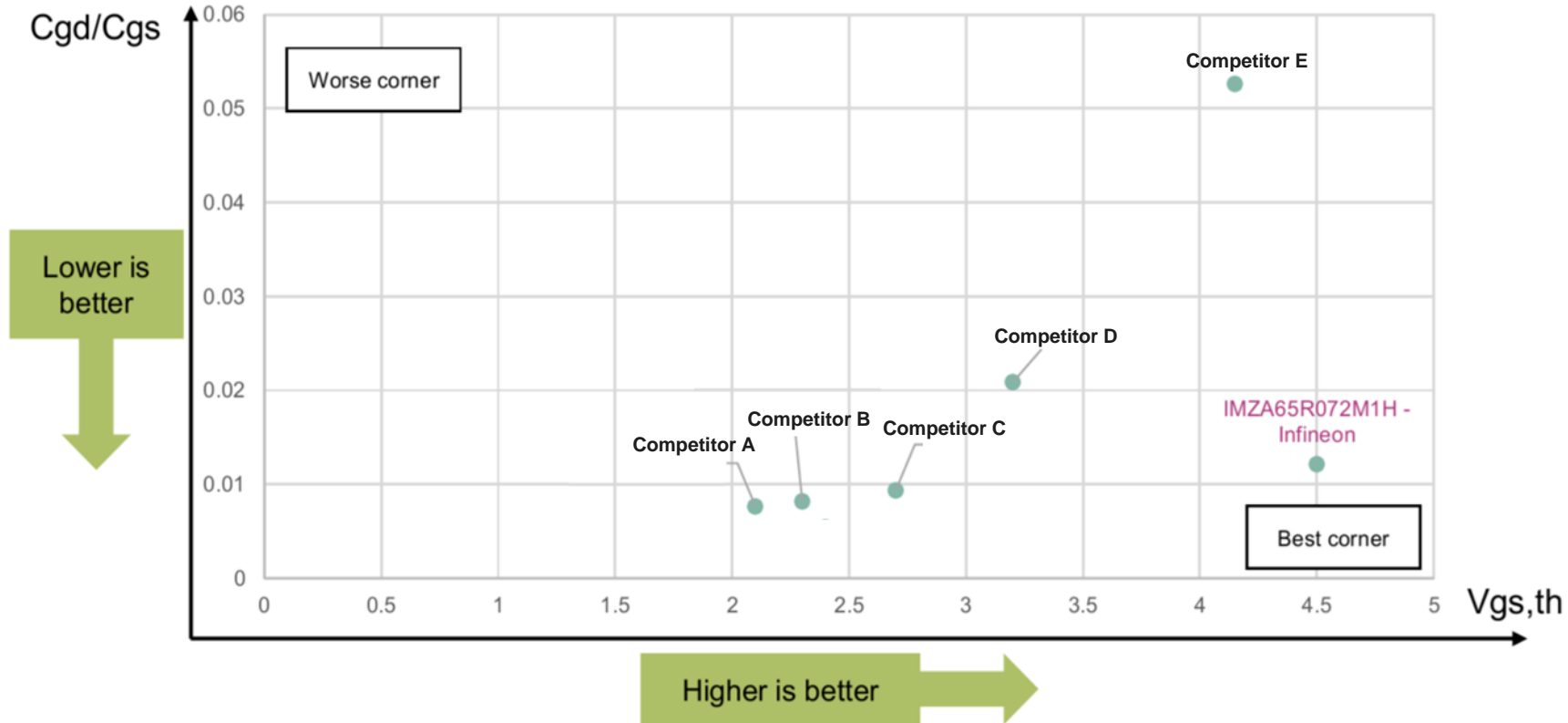


$$PTO\ factor = \frac{Q_{GD}@400V}{Q_{GS}@V_{gs}(t_h)25^\circ C}$$

Note: PTO factor calculated from datasheets. The graphs reports the best devices among the ones analyzed

Why 0V turn off voltage is possible with negligible parasitic turn-on effects?

Datasheet comparison of 650V SiC MOSFET devices having a nominal on-state resistance of 60-80 mΩ.

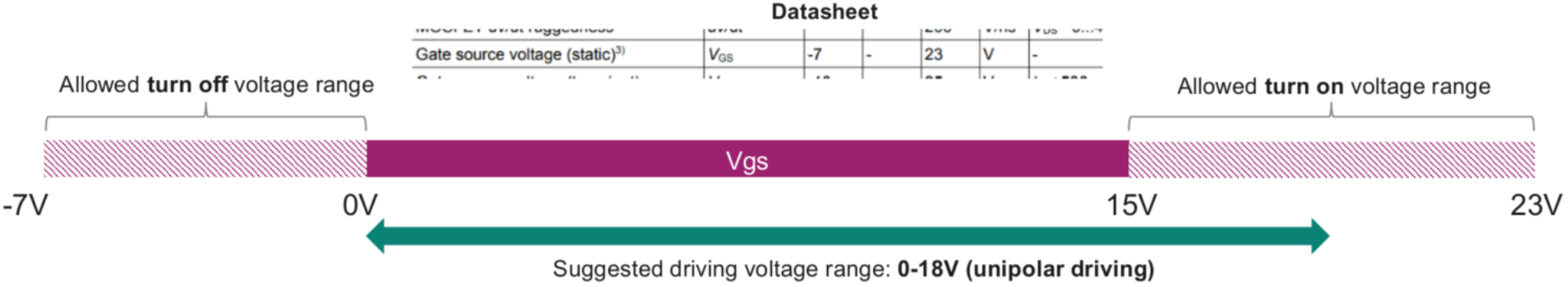


Best for reducing the parasitic turn-on:

- > higher $V_{gs(th)}$ – more margin against induced V_{gs} . The lower is the $V_{gs(th)}$ the higher is the probability to have a return-on
- > Lower capacitances ratio C_{gd}/C_{gs} – The lower is this ratio and the lower is the induced V_{gs}

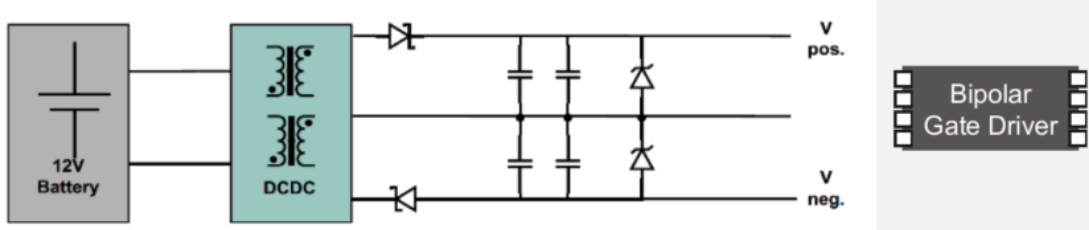
Putting the 2 results together, Infineon has *the best immunity against overall parasitic turn-on*

Flexible driving voltage

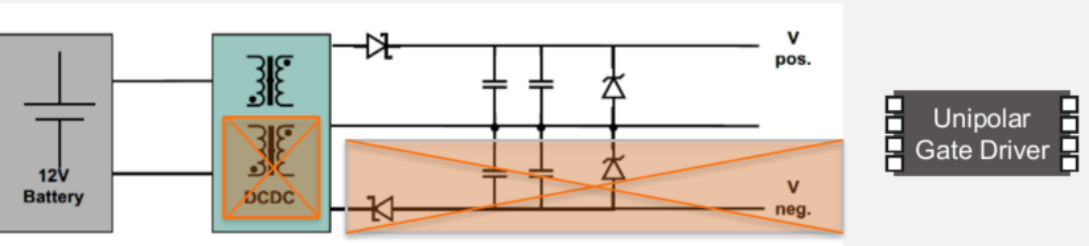


0V turn off voltage enables a more simplified and cheaper driving scheme

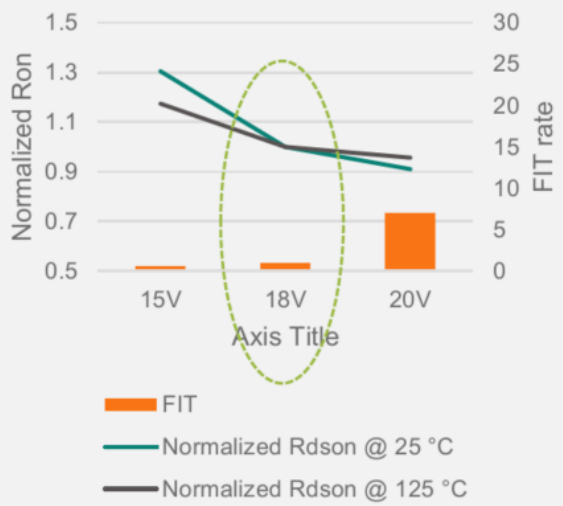
Negative gate voltage turn off



0V gate voltage turn off



18V turn on is the most optimized choice for performance, reliability and compatibility



- Rdson increases at 15V (by 17% @ 125°C)
- This behavior is the same for all SiC MOSFET brands
- FIT rates are very low also at 20V

**1 FIT = 1 failure expected per 10⁹ device hours of operation (e.g. 1M pieces over 1000 operating hours)

CoolSiC Trench MOSFET: FoM comparison: Gen 1 vs Gen 2



Parameter	IMZA65R057M1H 57 mΩ,typ Gen1		IMZA65R057M2H 57 mΩ,typ Gen2	Comparison (Gen2 vs Gen1)
Q_{oss} @ 400 V	65		46	~-30%
E_{oss} @ 400 V	9.8	Reduced switching losses	6.5	~-35%
C_{iss} @ 400 V	930		695	~-25%
C_{rss} @ 400 V	11		6	~-45%
(C_{rss}/C_{iss}) @ 400 V	0.012	Reduced sensitivity to PTO*	0.008	~-30%
$V_{(GS)th}$	Same target $V_{(GS)th} \sim 4.5V$ @ 25°C			~0%

- > Gen1: datasheet values.
- > Gen2: **characterization data based on EES with not final process**
- > * parasitic return-on

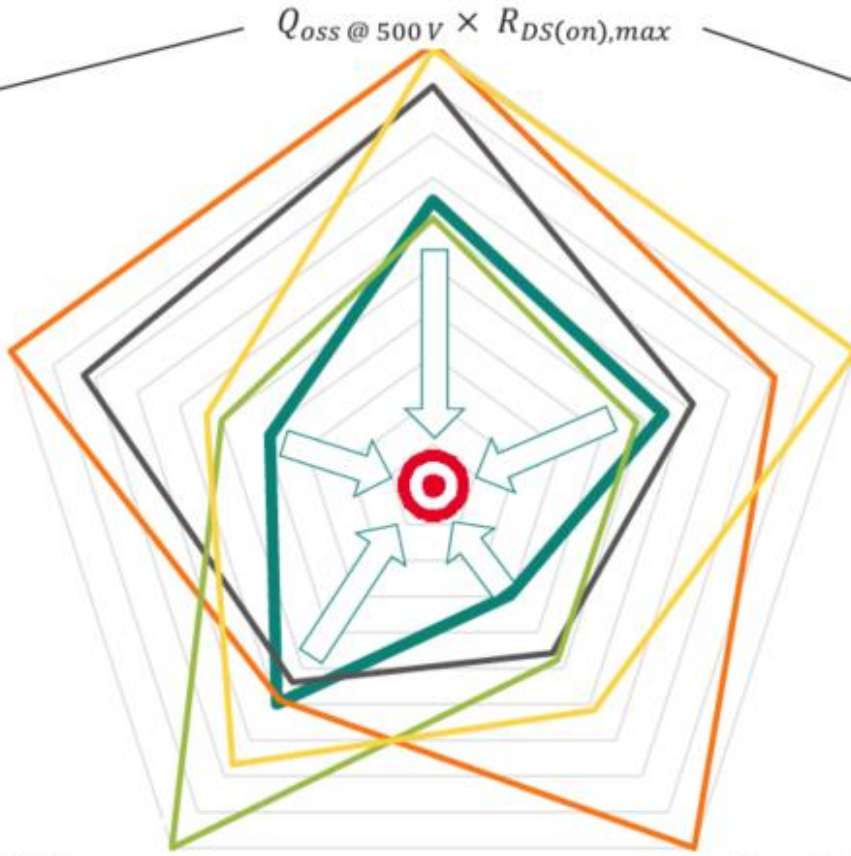
CoolSiC™ is the most balanced technology combining ease of use, switching efficiency and superior thermal performances



■ Infineon CoolSiC
 ■ Competitor A
 ■ Competitor B
 ■ Competitor C
 ■ Competitor D

Increased efficiency in the application through reduced dead-time and reduced circulating current in resonant topologies (e.g LLC)

Reduced switching losses in hard switched topologies



Enables unipolar driving
 No need for negative off state voltages → simpler and cheaper driving circuit

Increased power density, more power for same package footprint

Increased light load efficiency in soft switching topologies
 Enables usage of gate drivers with lower current capability for same switching speed

$$\frac{Q_{GD,@ 500 V}}{Q_{GS @ v_{th,typ}}}$$

$$\frac{R_{th,(j-c),max}}{R_{DS(on),max}}$$

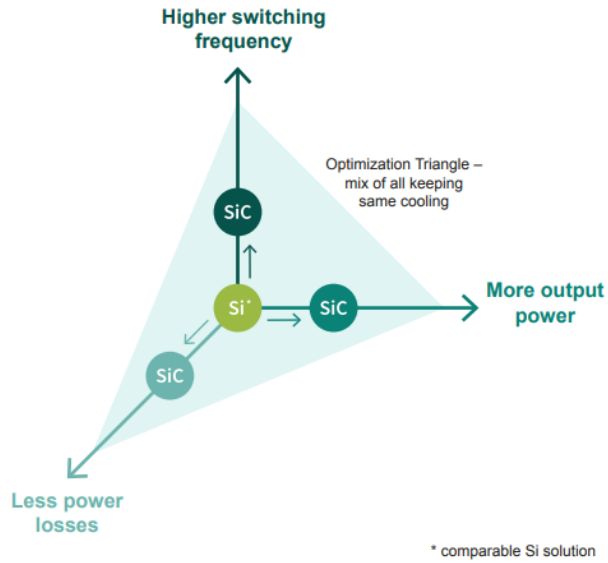
$$Q_{oss @ 500 V} \times R_{DS(on),max}$$

$$E_{oss @ 500 V} \times R_{DS(on),max}$$

$$E_{gate} \times R_{DS(on),max}$$

**Gen1 vs Gen2 Efficiency Comparison in
EV Charger's DCDC topology...
(Page 15-28)**

SiC power semiconductors are the perfect answer to many of today's and tomorrow's DC EV charging requirements and trends



Reduced system size



Lower system cost



Most efficient power conversion



EV charging

Common today	In rollout	Tomorrow						
Harsh operating modes <p>up-to 100k cycles / lifetime Changing operation modes High temperature cycles</p>	Higher efficiency Wide voltage scalability Higher efficiency 96% >> 98% @ various operation modes Wide voltage output 150 V > 1000 V support with wide efficiency plateau High power density to enables high space utilization	Bi-directionality Energy integration V2X (bi-directional) - Energy integration Megawatt charger - Higher voltages (1250 V) - Higher currents (up-to 3000 A) - V2X (bi-directional)						
Reliability, harsh environment Harsh environment: IP65, -45 °C - 55 °C Cooling optimization Reducing fans improves reliability and noise (<50 dBA)	High modularity and scalability <table border="1"> <tr> <td>22 kW</td> <td>30 kW</td> </tr> <tr> <td>50 kW</td> <td>75 kW</td> </tr> <tr> <td>75 kW</td> <td>100 kW</td> </tr> </table> Easy upgradability, scalability	22 kW	30 kW	50 kW	75 kW	75 kW	100 kW	EV Wireless Charging (?) Static & dynamic wireless power transfer (WPT) - 3.7 to 500 kW for cars and CAV
22 kW	30 kW							
50 kW	75 kW							
75 kW	100 kW							

EV charging is a key strategic application for Infineon

We cover the full ecosystem from AC to high power DC charging



Connectivity & Control

Automotive systems

High power industrial systems

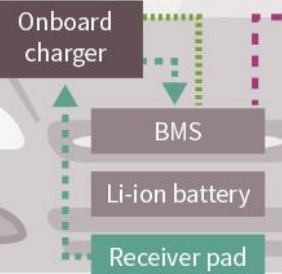
AC charging transfers power from a standard outlet
Ideal for residential charging

< 3.6 kW

< 22 kW

< 11 kW

Wireless Charging



DC wallbox

7-25 kW

DC High Power Charging

20 kW to 350 kW

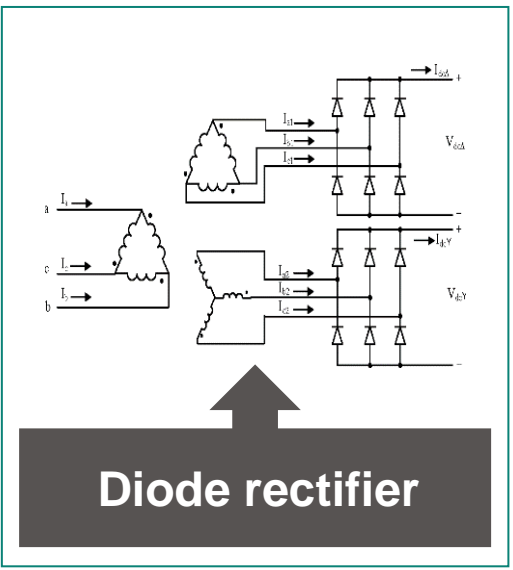
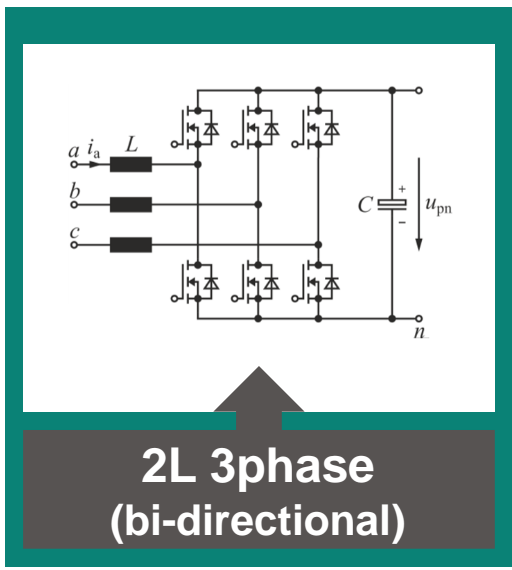
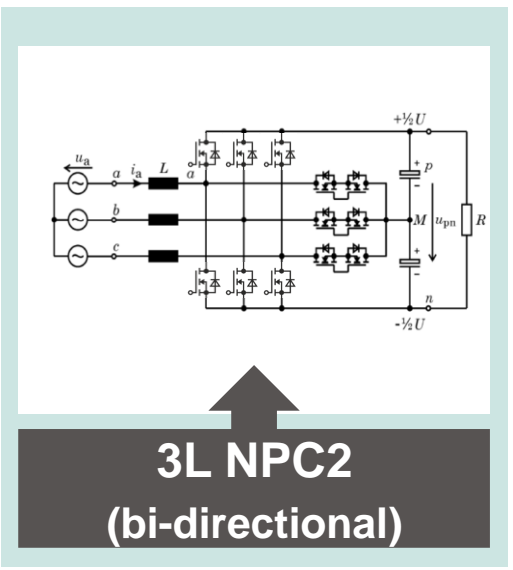
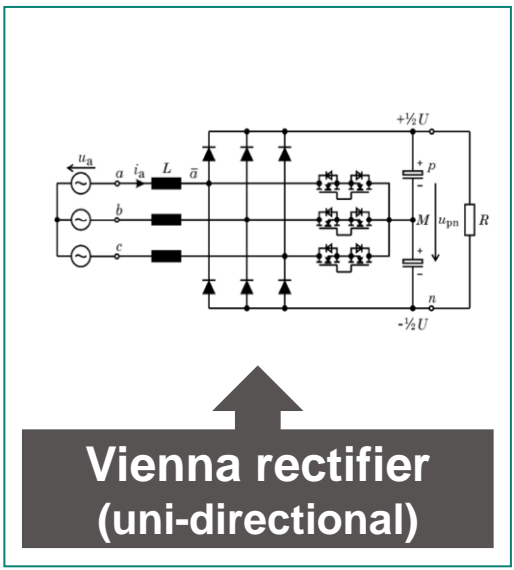
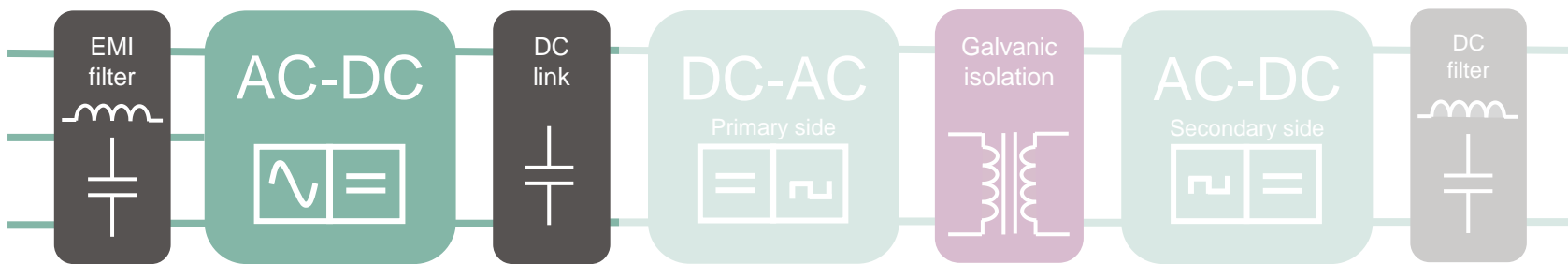
HPC

The focus use-case of our 22 kW reference design is a **bi-directional DC Wallbox**

Infineon targets the complete EV charging ecosystem from AC to high-power DC

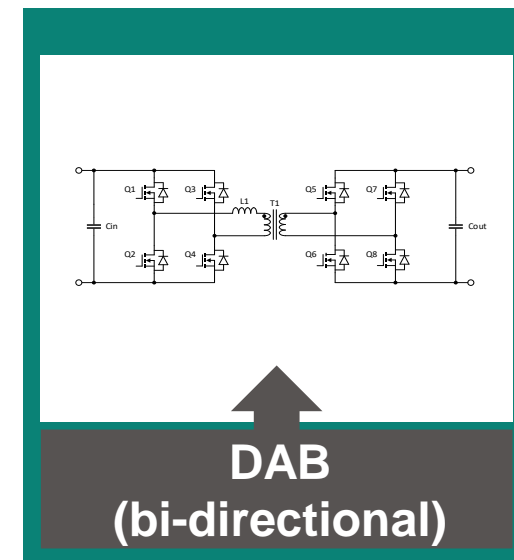
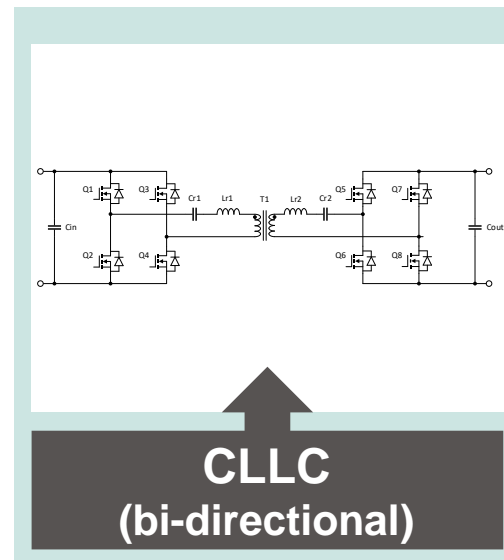
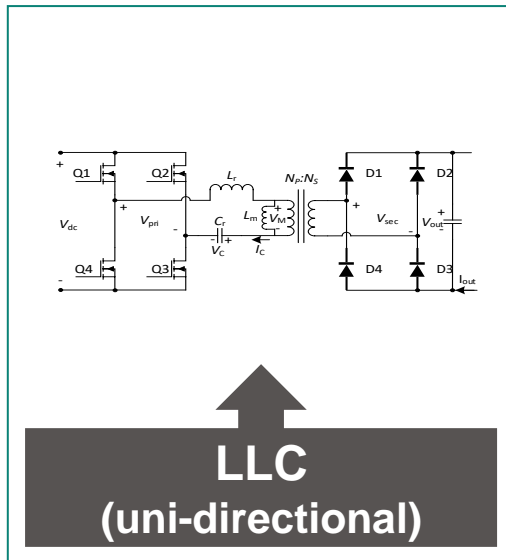
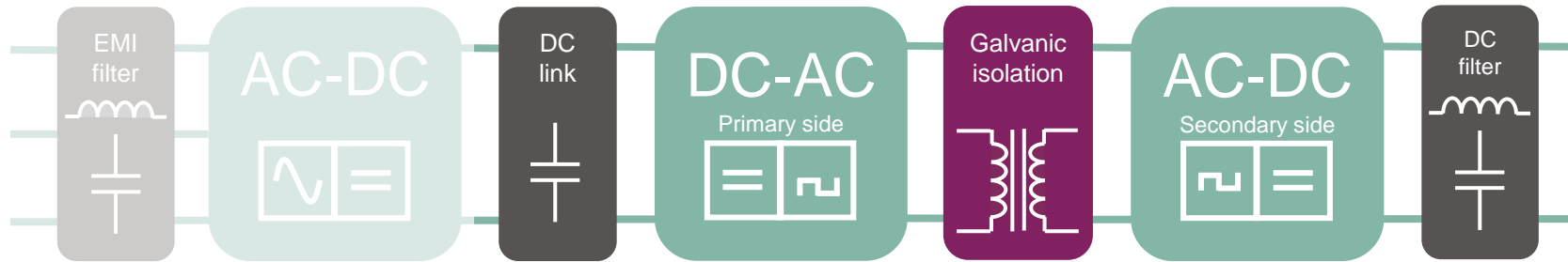
3 Level NPC2 and 2 Level 3phase are the most common PFC topologies for bi-directional DC EV Charging

Most common PFC topologies for EV Charging



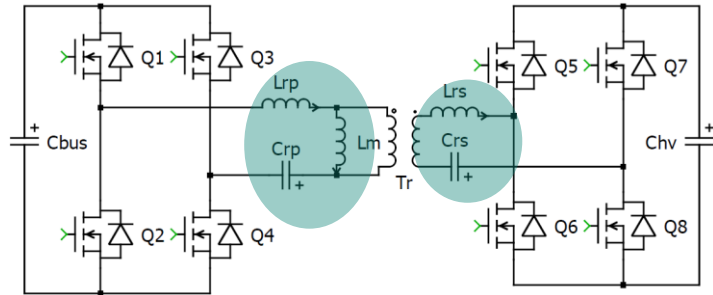
CLLC and Dual Active Bridge are the most common DC-DC power conversion topologies for bi-directional DC EV Charging

Most common DC-DC power conversion topologies for EV charging



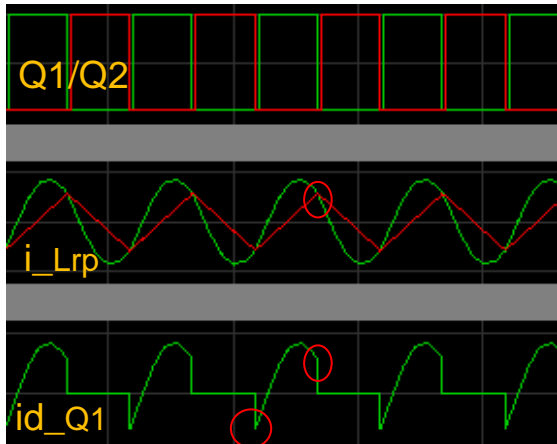
Comparison of full bridge CLLC and full bridge / 3-phase DAB: Hardware design

Full bridge CLLC

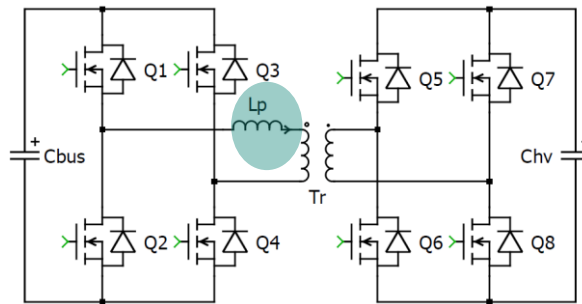


$$L_{rs} = L_{rp} / n^2, C_{rs} = C_{rp} \cdot n^2$$

PFM control:

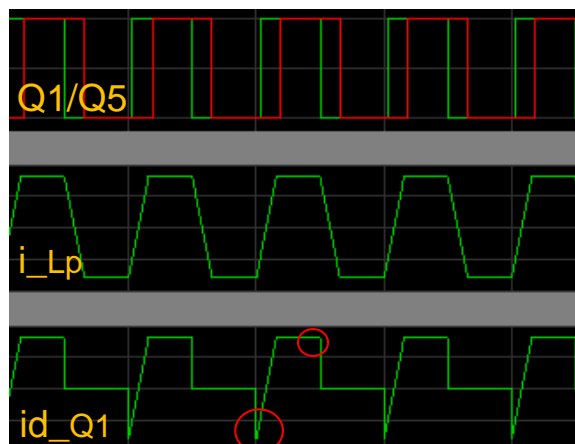


Full bridge DAB

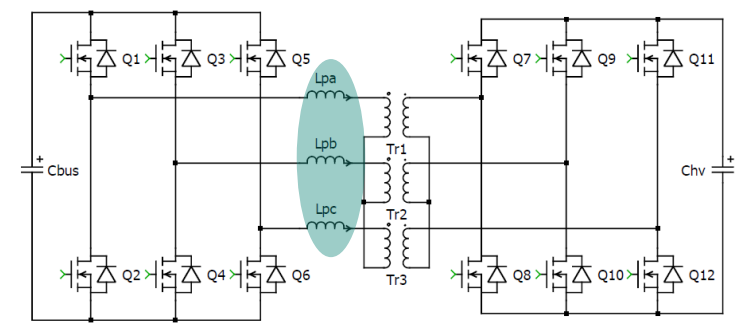


$$L_p = \frac{nV_{bus}V_{hv}D(1-D)}{2f_sP_o}$$

SPS control:

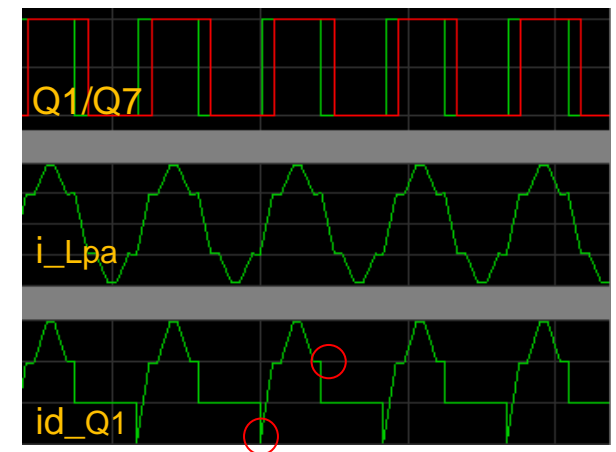


3-phase DAB (Y-connected)



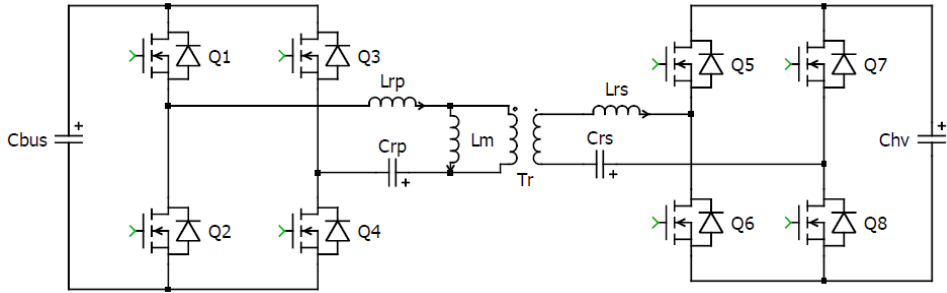
$$L_{pa} = L_{pb} = L_{pc}$$

SPS control:

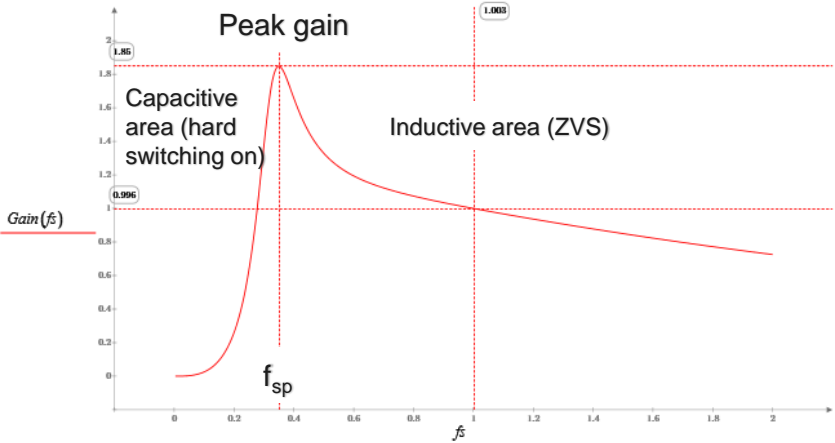


Full bridge CLLC ZVS (Zero Voltage Switching) region

Full bridge CLLC

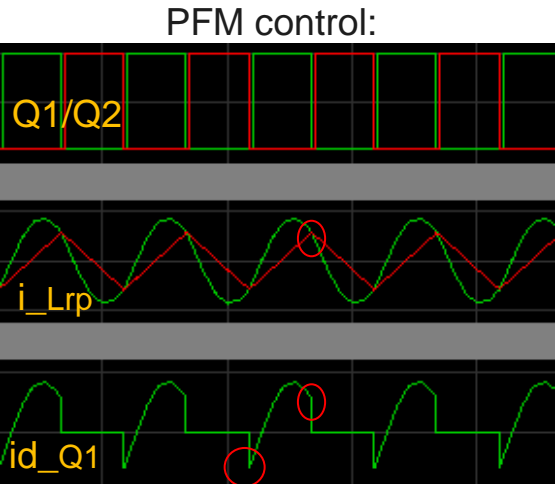


PFM control for CLLC, aims to control the voltage gain

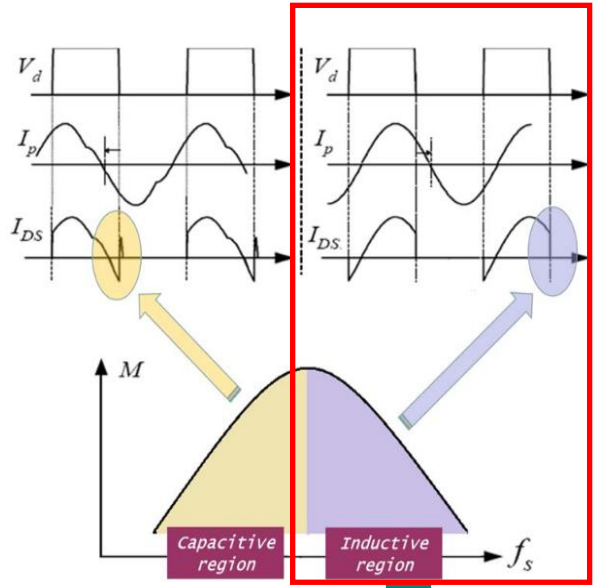


When $f_s > f_{sp}$, both the monopoly of voltage gain and ZVS of primary MOSFET can be achieved

CLLC Waveform



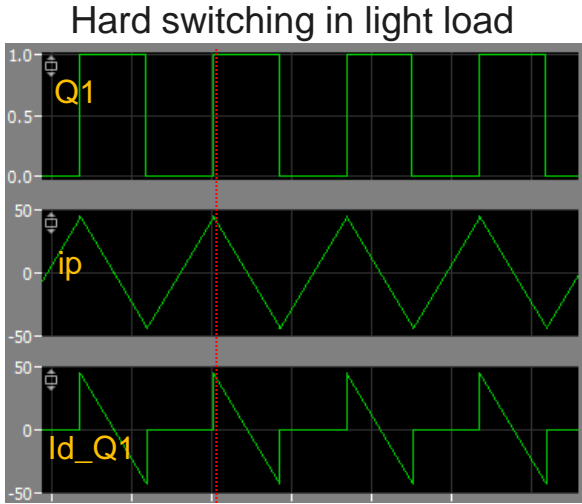
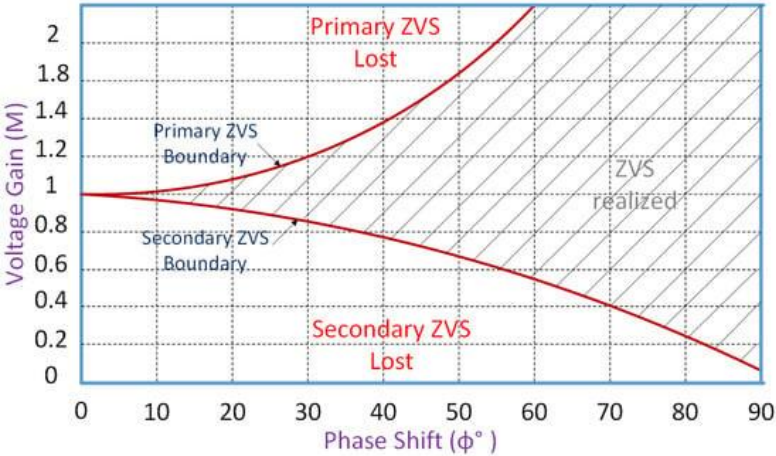
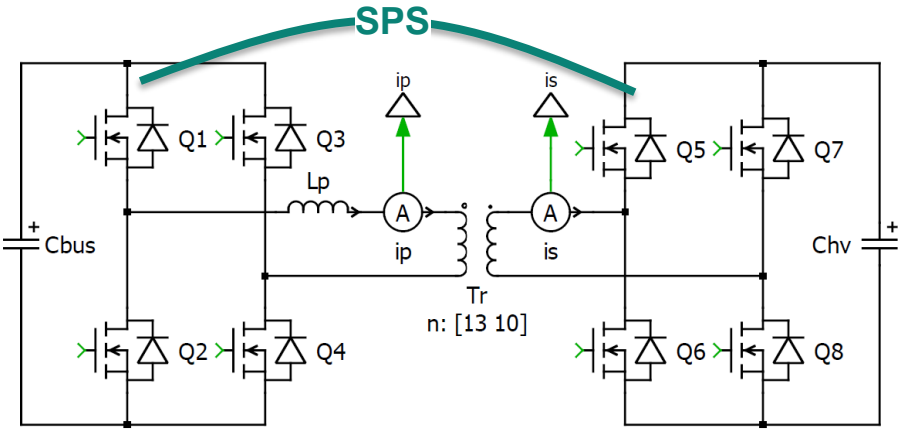
- EMI design: easy
- Flat efficiency curve
- Easy ZVS



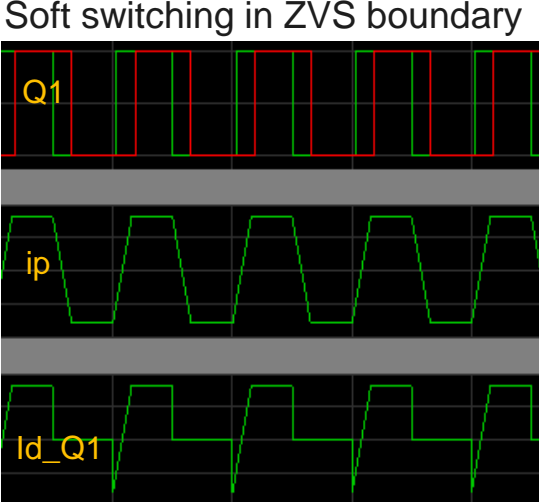
When turn on, ZVS (O)
When turn off, ZVS (X)

DAB Hard switching region

Fundamental challenge: DAB loses ZVS soft switching, according to ZVS boundary. Light load is worst for ZVS



No ZVS



Output voltage: 1000 V		
Output load	0.5kW	15kW
Turn-on current of Q1	43.3A	26.1A
RMS current of Q1	17.9A	20.7A
Losses of Q1	116W	76.4W

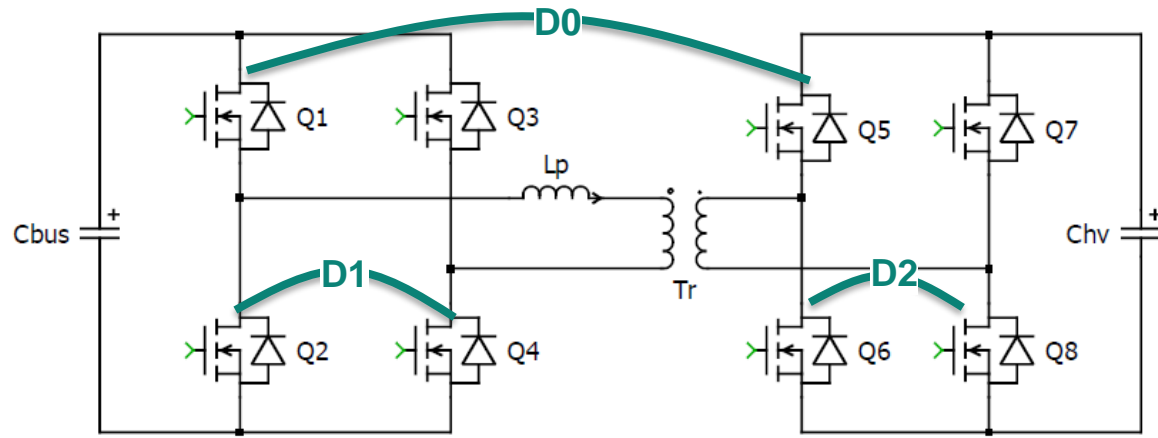
- Light load is the worst condition when $V_{in} \neq n \cdot V_o$
- MOSFET can not endure the high loss at light load

Gen 2 will be best which has low switching loss to cover the wide load

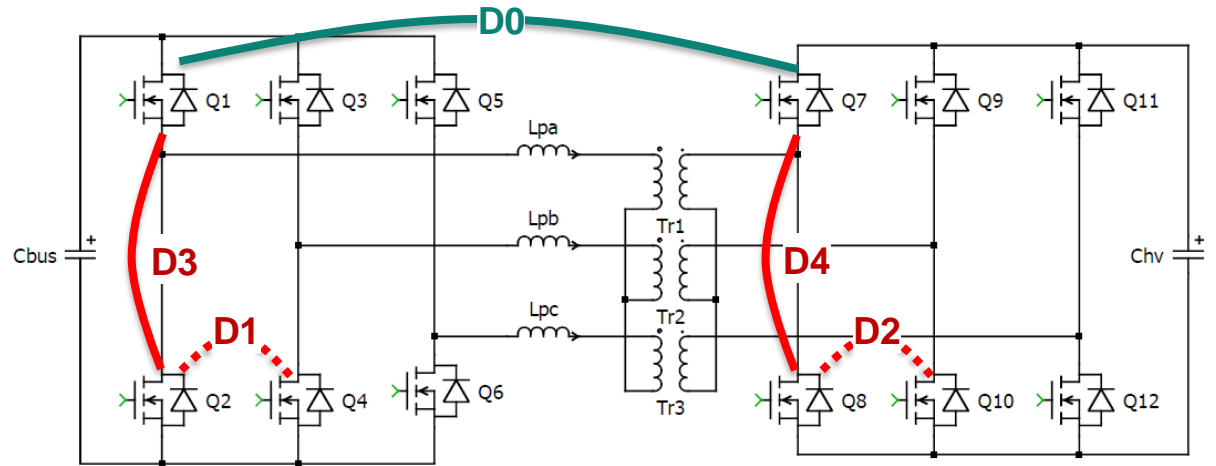
Control concept for DAB and 3-phase DAB: New approach for control algorithm design

Solution: adopt more control freedom based on a reasonable optimization objective, for example minimizing the turn-on current

For full-bridge DAB



For 3-phase DAB



An intrinsic phase shift (D1/D2, 120°) already exists in 3-phase DAB

Control method	Control freedom	Degrees of control freedom
SPS	D0	1
DPS	D0, only D1 or D2	2
EPS	D0, D1=D2	2

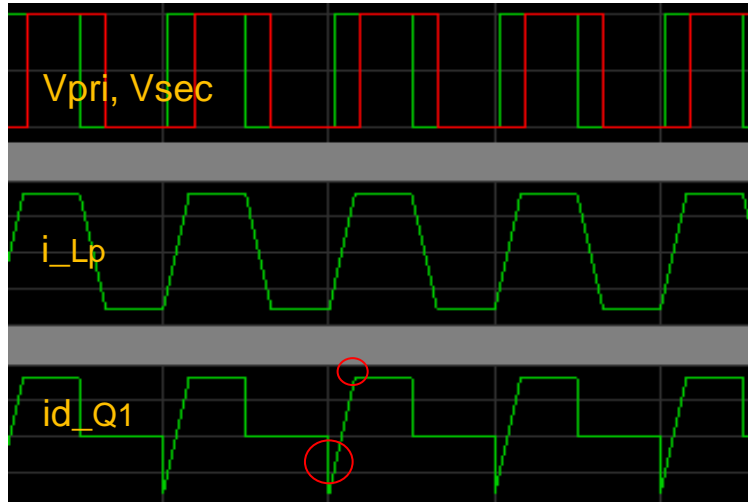
Control method	Control freedom	Degrees of control freedom	Applicable condition
IFX method #1	D0, D3=D4, symmetric PWM	2	$V_{in} > n \cdot V_o$
IFX method #2	D0, D3=D4, complementary PWM	2	$V_{in} < n \cdot V_o$

New approach : 2 control freedom + software simplicity

Control concept of DAB with Gen1 vs Gen2 SiC Efficiency Comparison

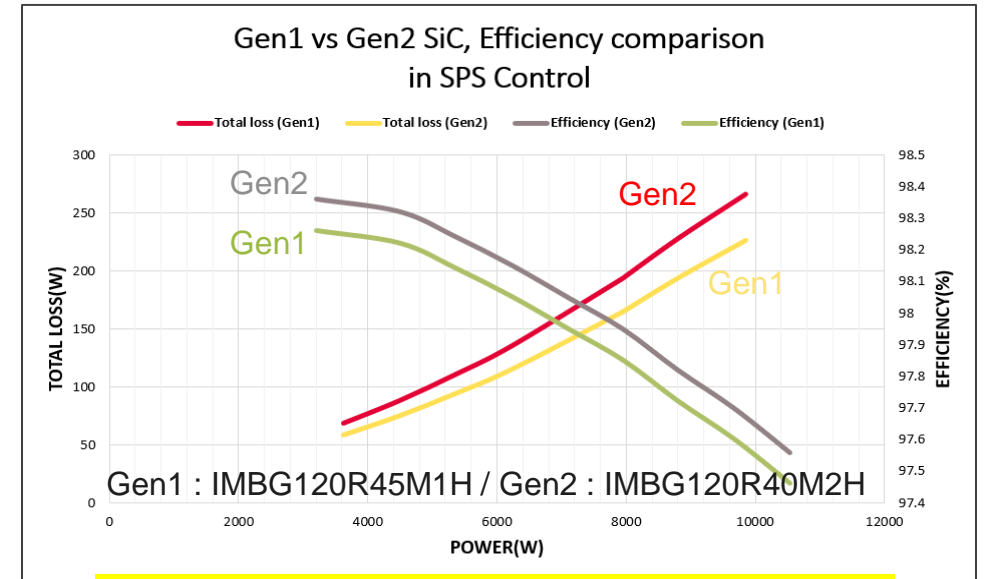
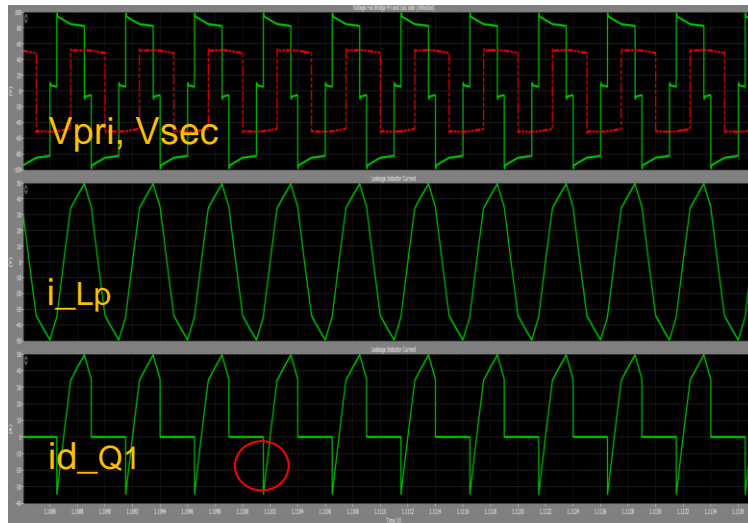
**DAB
SPS
control**

SPS control:

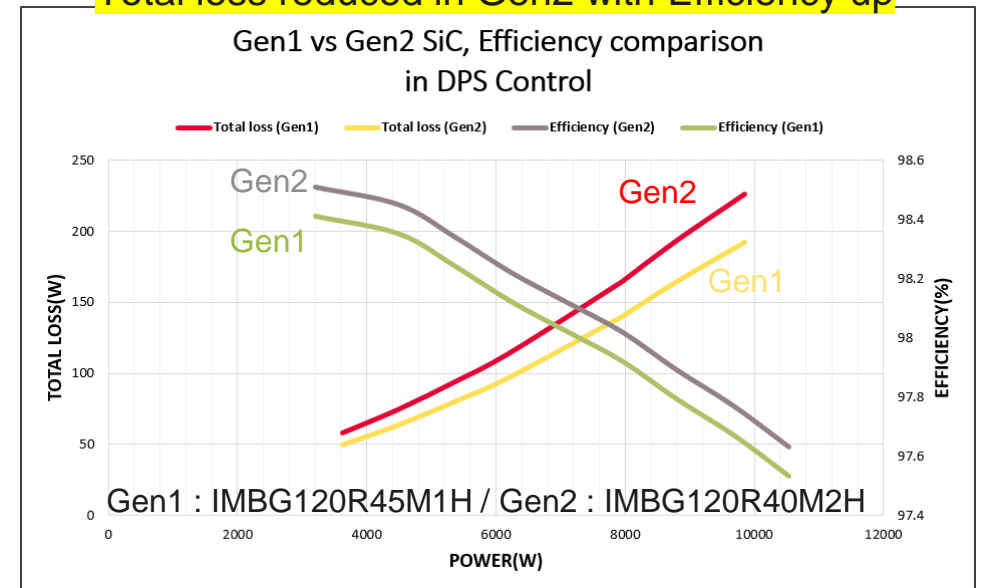


**DAB
DPS
control**

DPS control:



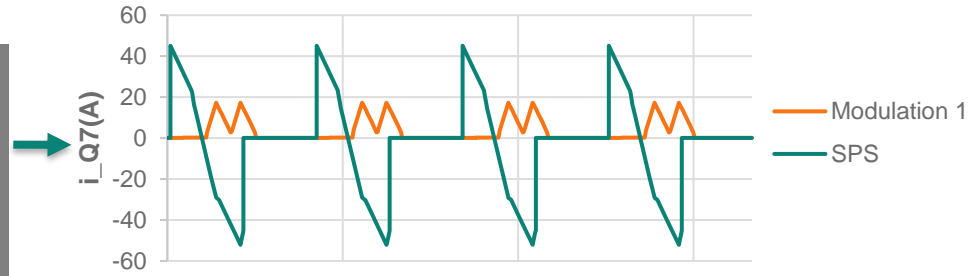
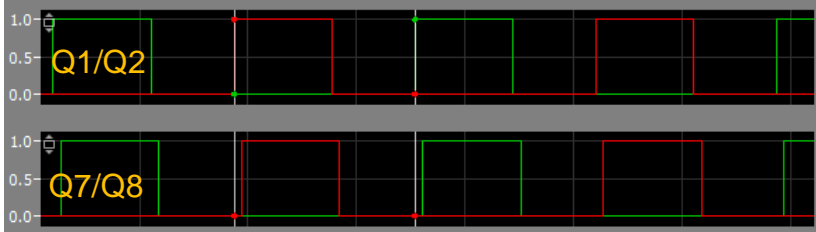
Total loss reduced in Gen2 with Efficiency up



Control concept for 3-phase DAB: Implementation and results of new control algorithm

3-Phase DAB control

Modulation scheme 1: SPS + symmetric PWM
(D0, D3=D4, when $V_{bus} > n * V_{hv}$)



at $V_{bus} = 680\text{ V}$, $V_{hv} = 200\text{ V}$, load = 2 kW

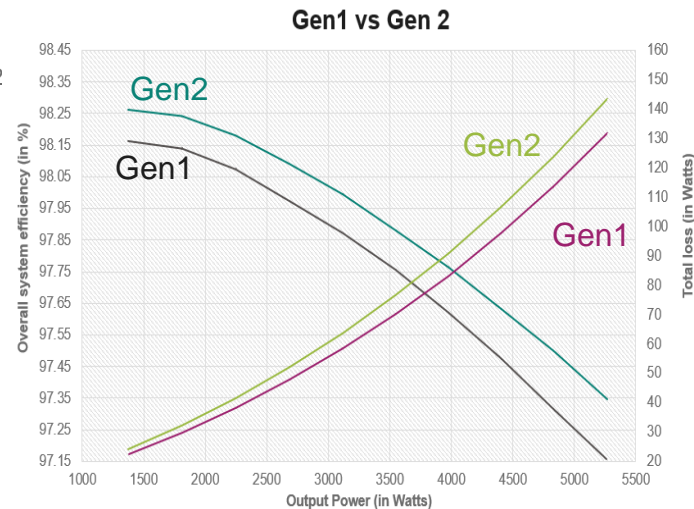
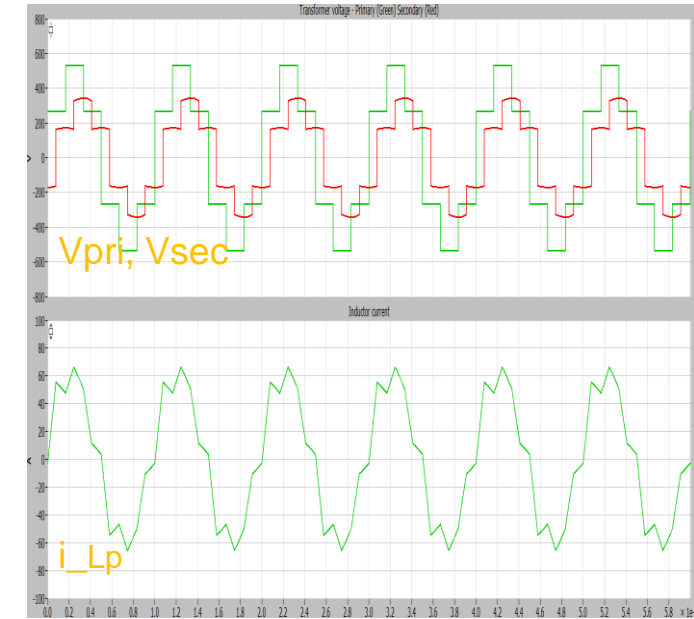
Result: turn-on current of Q7 is reduced from **45.2 A** to **-3.1 A**

Modulation scheme 2: SPS + complementary PWM
(D0, D3=D4, when $V_{bus} < n * V_{hv}$)



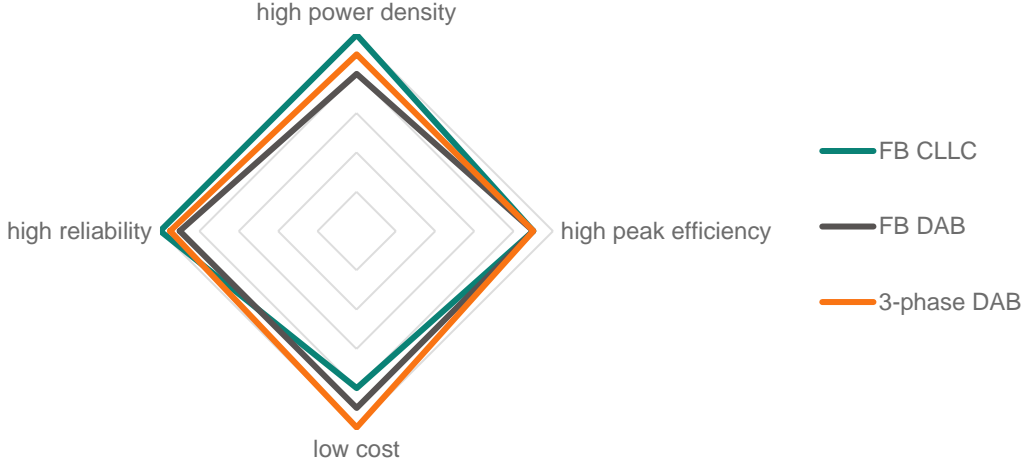
at $V_{bus} = 900\text{ V}$, $V_{hv} = 900\text{ V}$, load = 1 kW

Result: turn-on current of Q1 is reduced from **24.7 A** to **7.2 A**



Summary of CLLC and full bridge / 3-phase DAB:

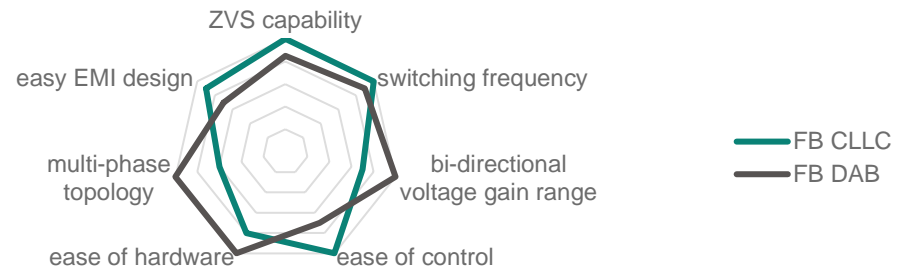
Top level assessment



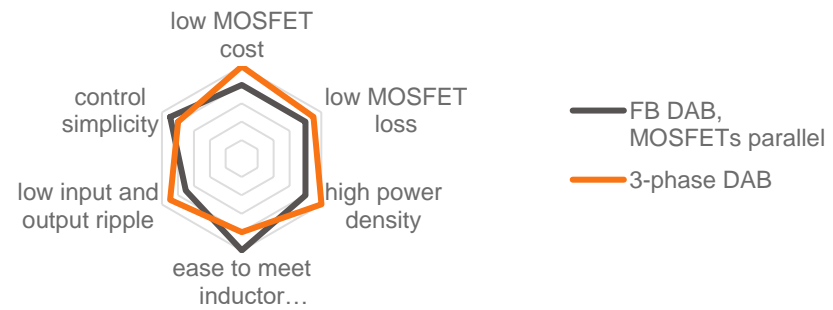
Main conclusions:

1. CLLC is the best choice, if high switching frequency, high power density and good EMI performance need to come together, and a narrow output voltage range is acceptable.
2. The key advantage of DAB for the use case of DC EV charging is its combination of wide output voltage range with a decent efficiency in both directions, and lower cost.
3. 3-phase DAB comes with the lowest semiconductor and passive component costs, but needs special care on the control concept

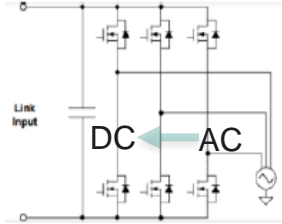
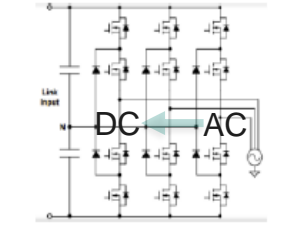
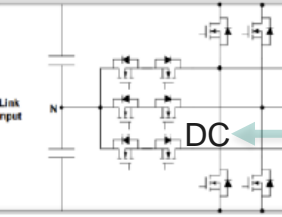
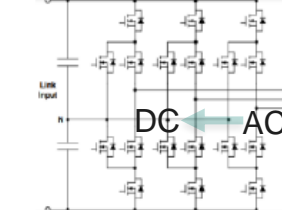
Full-bridge CLLC versus full-bridge DAB

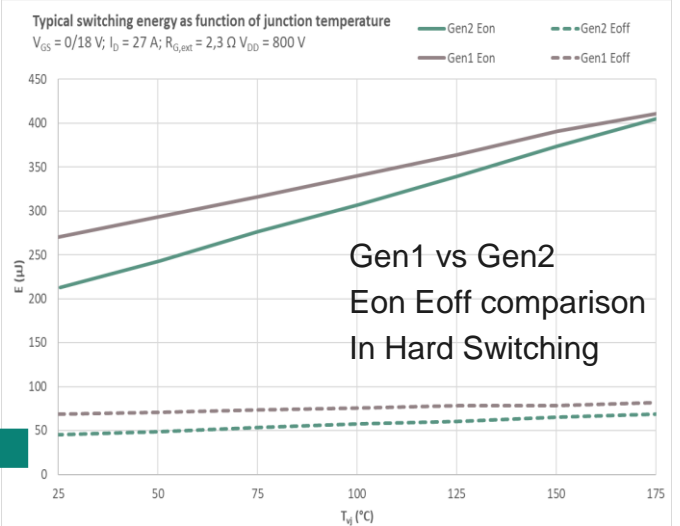
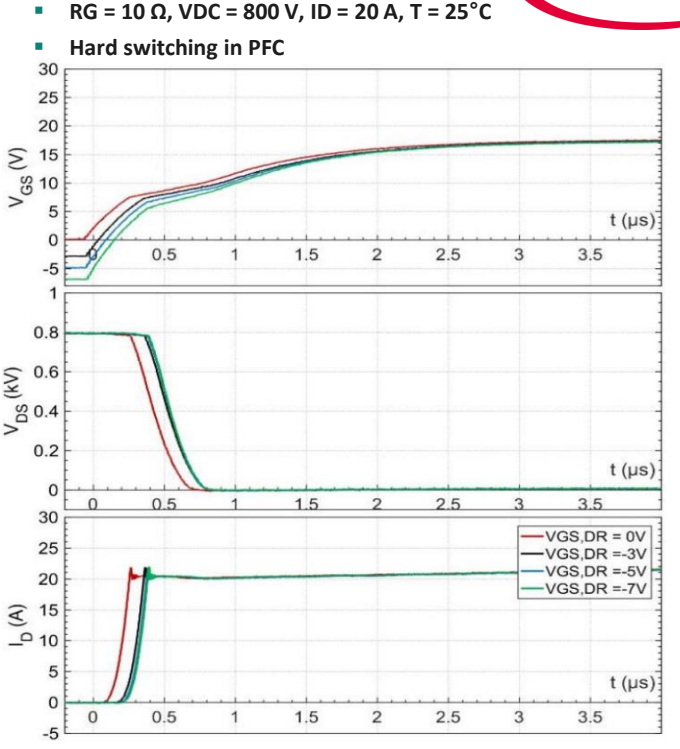


Full-bridge DAB versus 3-phase DAB



PFC Topology comparison and hard switching

Topology	Properties
<p>Two level h-bridge</p> 	<ul style="list-style-type: none"> - Simple, well known architecture - Low component cost - Simple control structure - Losses are concentrated in few devices - Link voltage limited to component voltage rating
<p>Three level NPC 1</p> 	<ul style="list-style-type: none"> - Stacks multiple switching devices to half the voltage blocking capability needed - Able to use lower voltage/cost devices - Neutral point clamp centers switching devices - Unequal component loss distribution - Increased conduction loss - More complex control structure
<p>Three level NPC 2 / TNPC</p> 	<ul style="list-style-type: none"> - Reduced switching device count - Lower conduction loss - Simplified driver bias supply vs NPC1 & ANPC - Simplified control structure vs NPC 1 and ANPC - Primary switches still experience full DC link voltage (blocking)
<p>Three level ANPC</p> 	<ul style="list-style-type: none"> - Clamping diode replaced with active device - Similar benefits of NPC 1 - More complex control structure - Similar losses to NPC 1 but balanced across devices - Increased conduction loss



Hard switching in PFC topology, **switching performance improvement is more important for system efficiency up**

Actual Switching waveform

Gen1 and Gen2

Actual switching waveform Comparision

